

Applied Beams LLC

Applied Beams LLC is a leading supplier of FIB and SEM consumables, custom-configured systems, and micro-machining services, and we bring new life to your SEM and FIB system with our upgrades that extend and enhance system performance. With 30+ years of experience with ion and electron beam systems design, manufacture and applications we provide a unique ability to meet customer needs with these powerful technologies.

We serve the semiconductor, materials analysis and research communities, and proudly support the US Government with our unique ability to develop and deliver custom FIB and SEM systems.

- **HyperFIB upgrade**—Our high-current HyperFIB system is the only plasma FIB upgrade on the market for legacy FIB tools, increasing available current for micromachining, cross-sectioning and material deposition from just 20nA to over 7uA, an improvement of 350X!
- **Consumables**—Our high quality, affordable consumables are direct replacements for original components, keeping your FIB, SEM and dual column FIB-SEM systems operating at optimum performance and on budget.
- **Scanning electron microscopes**—We've brought the CamScan Electron Optics electron microscopes back to market and offer customized versions of the popular CS-series of SEMs. Derived from CamScan Helios™ software, our Caesium™ control system provides new features including up to 20 images displayed per Window, drag and drop image open and save, and support for advanced techniques such as our Quantitative EBIC Measurement System. Caesium also brings your SEM into the 21st century with a client-server architecture on the Microsoft Windows 7 operating system.
- **Micromachining and analytical services**—Our micromachining services utilize our unique HyperFIB systems. With up to 7uA of beam current this tool is perfect for preparing cross-sections of advanced semiconductor devices and delayering all or a portion of a semiconductor device.

Buy with confidence. Our customers include Fortune 500 companies, top research institutions and government laboratories.



APPLIED BEAMS



Liquid Metal Ion Sources



Detectors



FIB and SEM Aperture Strips



Plasma FIB Upgrades

How to find us

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